

Distribution	Ärende/Item	Datum/Date	Reg.nr/Reg.No.	Rev	Sida/Page
Art. No. 3643-0215	Reliability Prediction Report LynxDSS_L205-S1	2013-04-04		0	1(1)
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LynxDSS_L205-S1 Reliability Prediction Data

Environment	MTBF 25°C [hours]	MTBF 40°C [hours]
GB	676 669	659 705

Device predicted

5011-1060-B-01 LynxDSS Power 4-layer
5011-1200-B-02 LynxDSS entry level S1

Prediction Method

MIL-C217F2, Parts count.

Quality levels

Component type	Quality level
Passive R,C	R
Inductive	MIL
Connectors	MIL
Discrete semiconductors	JANTX
Microcircuits (IC)	Toolkit ¹

¹Toolkit, i.e. reliability prediction based on FIT (Failure In Time) values obtained from IC manufacturer. FIT values are used according to ROME LABORATORY RELIABILITY ENGINEER'S TOOLKIT, Temperature Conversion Factors (Table A11-3). FIT = 15 might be used until manufacturer data is obtained.

Environment

GB, Ground Benign

Enclosure

MTBF Pareto Report, Components contribution to total Failure Rate (>1%).